Search Notes				
1 (15) 11 (15) 61(16)	ANN BAIDH IIBH GBITH (BIB) BIN 1811			

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/601,085	JAIN ET AL.	
Examiner	Art Unit	
Matthew D. Matzek	1771	

SEARCHED					
Class	Subclass	Date	Examiner		
442	5-9	Wiofot	MM		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	1/13/2005	мм	
LPDATED	1./1./	мм	
Inventor Search	1/13/2005	ММ	
ASSIGNEL.	10/10/05	MM	
IDS	1/14/2005	мм	
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